

# WT3415

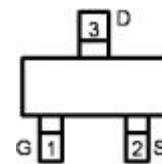


20V P-Channel MOSFET

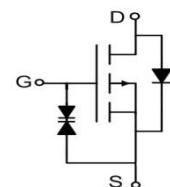
ID(max)=4A,  
BVDS=20V,  
RDS(on)=37mΩ @VGS =-4.5V  
RDS(on)= 50mΩ @VGS =-2.5V



SOT23



Marking and pin  
Assignment



Schematic diagram

## General Description

### Features

- Low on-state resistance
- ESD Rating: 2500V HBM
- High Power and current handing capability
- Lead free product

These P-Channel enhancement mode power field effect transistors are produced using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance and gate charge, provide superior switching performance and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for battery protection, load switching, power management and a wide variety of other applications.

### Absolute max Ratings(TJ = 25°C unless otherwise noted)

Symbol	Parameter	Units	Maximum
V <sub>DS</sub>	Drain-Source Voltage	V	-20
V <sub>GS</sub>	Gate-to-Source Voltage	V	±10
I <sub>D</sub> @ TC = 25°C	Continuous Drain Current, VGS @ -4.5V ①	A	-4
I <sub>D</sub> @ TC = 100°C	Continuous Drain Current, VGS @ -4.5V ①	A	-3.2
I <sub>DM</sub>	Pulsed Drain Current②	A	-32
P <sub>D</sub>	Power Dissipation①	W	1.39
	Derating Factor①	W/°C	0.011
T <sub>J</sub>	Operating Junction Temperature Range	°C	-50 to + 150
T <sub>STG</sub>	Storage Temperature Range	°C	-50 to + 150

### Thermal Characteristics

R <sub>θJA</sub>	Maximum Junction-to-Ambient③④	°C/W	90
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### Electrical characteristics(TJ = 25°C unless otherwise noted)

Symbol	Parameter	Test conditions	Units	Min.	Typ.	Max.
V(BR) <sub>DSS</sub>	Drain-to-Source breakdown voltage	V <sub>GS</sub> = 0V, I <sub>D</sub> =-250μA	V	-20	—	—
R <sub>DS(on)</sub>	Static Drain-to-Source on-resistance	V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-4A	mΩ	—	—	50
		V <sub>GS</sub> =-2.5V, I <sub>D</sub> =-2A	mΩ	—	—	60
		V <sub>GS</sub> =-1.8V, I <sub>D</sub> =-2A	mΩ	—	—	90

		$V_{GS}=-1.5V, I_D=-0.8A$	$m\Omega$	—	—	110
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = -250\mu A$	V	-0.35	—	-0.9
$I_{DSS}$	Drain-to-Source leakage current	$V_{DS} = -20V, V_{GS} = 0V$	$\mu A$	—	—	-1
$I_{GSS}$	Gate-to-Source forward leakage	$V_{GS} = 10V$	$uA$	—	—	10
		$V_{GS} = -10V$		-10	—	—
$V_{SD}$	Diode Forward Voltage	$I_S = -1A, V_{GS} = 0V$	V	—	—	-1
$g_{FS}$	Forward Transconductance	$V_{DS} = -5V, I_D = -4A$	S	4	—	—

### Dynamic characteristics( $T_J = 25^\circ C$ unless otherwise noted)

Symbol	Parameter	Test conditions	Units	Min.	Typ.	Max.
$C_{iss}$	Input capacitance	$V_{GS} = 0V$ $V_{DS} = -10V$ $f = 1MHz$	$pF$	—	950	—
$C_{oss}$	Output capacitance			—	160	—
$C_{rss}$	Reverse transfer capacitance			—	120	—
$Q_g$	Total gate charge	$V_{DS} = -10V$ , $I_D = -4A$ , $V_{GS} = -4.5V$	$nC$	—	12	—
$Q_{gs}$	Gate-to-Source charge			—	1.4	—
$Q_{gd}$	Gate-to-Drain("Miller") charge			—	3.1	—
$t_{D(on)}$	Turn-On Delay Time	$V_{DD} = -10V$ , $I_D = -4A$ , $V_{GS} = -4.5V$ , $R_{GEN} = 5\Omega$	$ns$	—	12	—
$t_r$	Turn-On Rise Time			—	10	—
$t_{D(off)}$	Turn-Off Delay Time			—	19	—
$t_f$	Turn-Off Fall Time			—	25	—
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F = -4A$ , $dl/dt = -100A/\mu s$ , $T_J = 25^\circ C$	$ns$	—	37	—
$Q_{rr}$	Body Diode Reverse Recovery Charge		$nC$	—	334	—

- ① Based on  $T_{J(MAX)}=150^\circ C$  in a SOT23 package, using junction-to-ambient thermal resistance
- ② Repetitive rating, pulse width limited by junction temperature  $T_{J(MAX)}=150^\circ C$ .
- ③ The  $R_{\theta JA}$  is the sum of the thermal impedance from junction to case  $R_{\theta JC}$  and case to ambient.
- ④ These tests are performed with the device mounted on 1 in2 FR-4 board with 2oz. Copper, in a still air environment with  $TA=25^\circ C$ .

## Typical electrical and thermal characteristics:

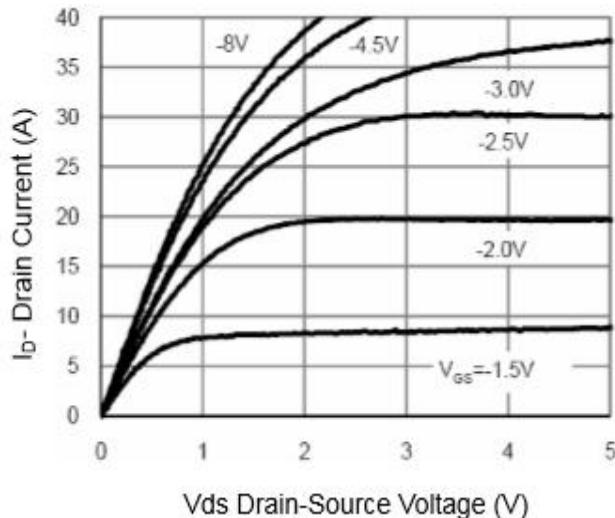


Figure 1: Typical Output Characteristics

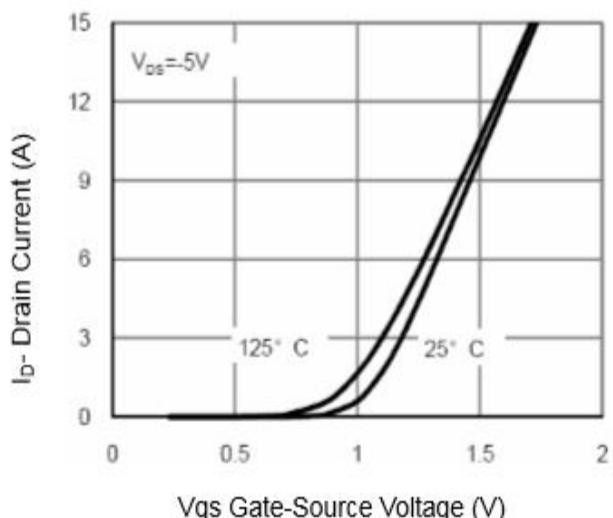


Figure 2: Typical Transfer Characteristics

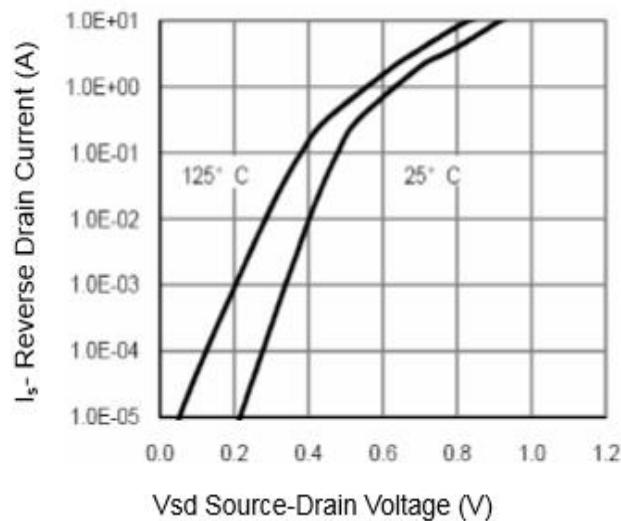


Figure 3: Body-Diode Characteristics

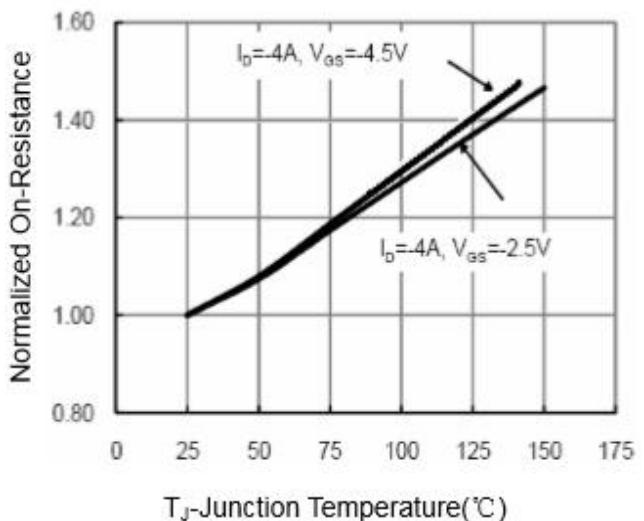


Figure 4: On-Resistance vs. Junction Temperature

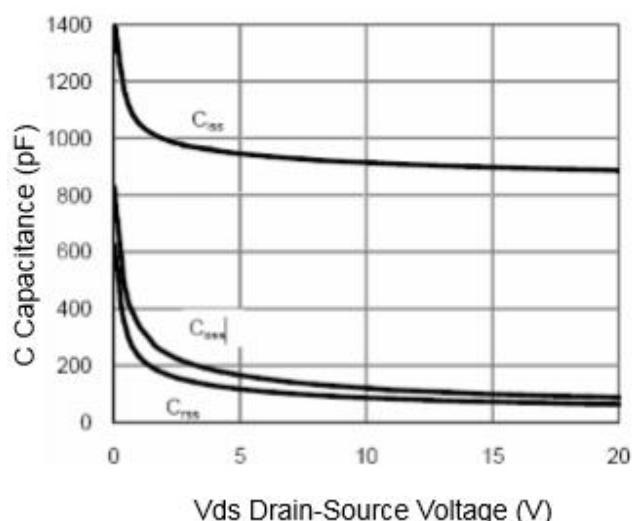


Figure 5: Capacitance Characteristics

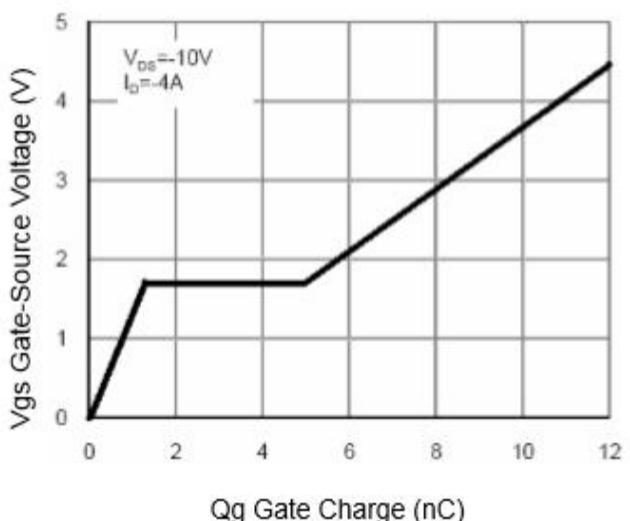
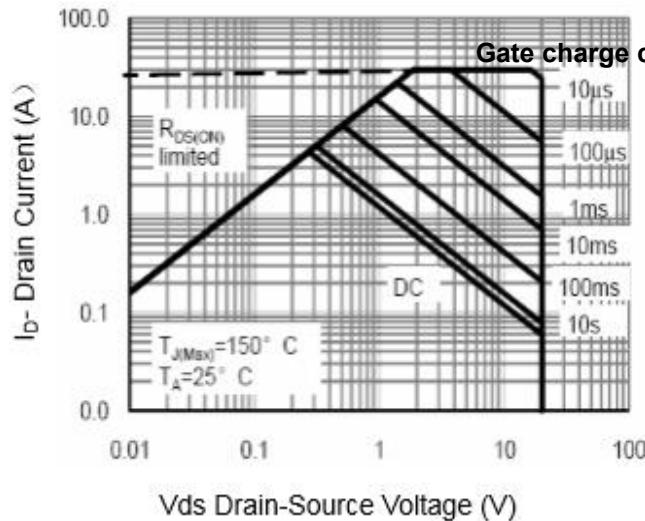
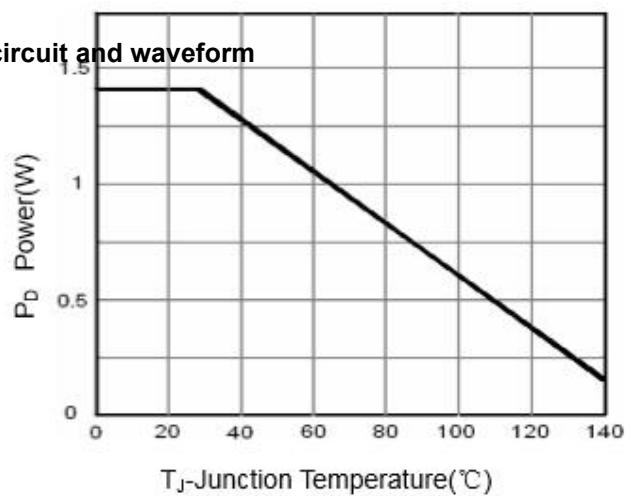


Figure 6: Gate-Charge Characteristics

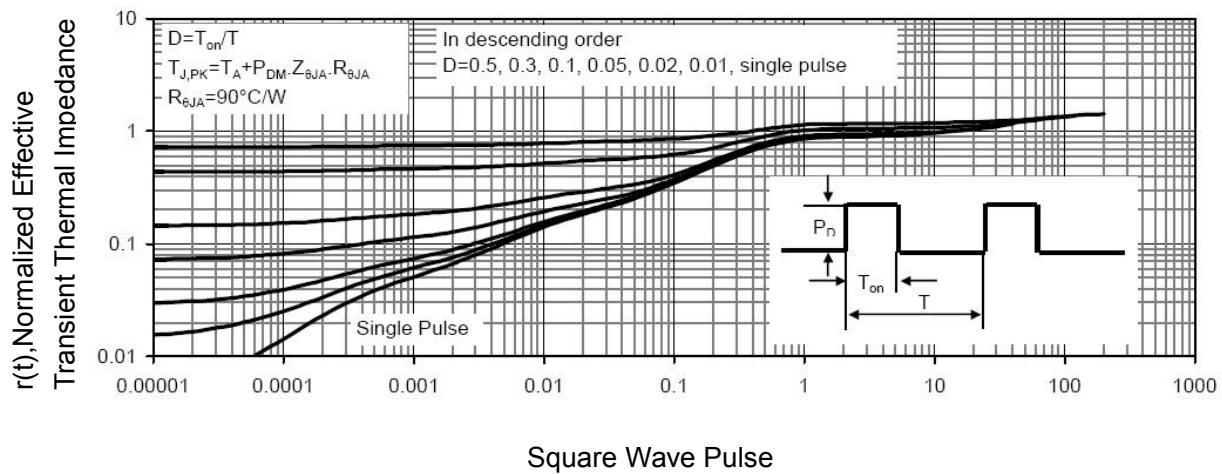
## Typical electrical and thermal characteristics:



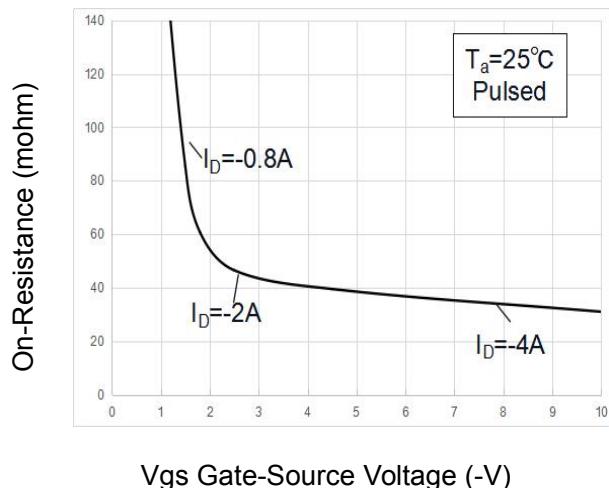
**Figure 7: Maximum Forward Biased Safe Operating Area**



**Figure 8: Power Dissipation**



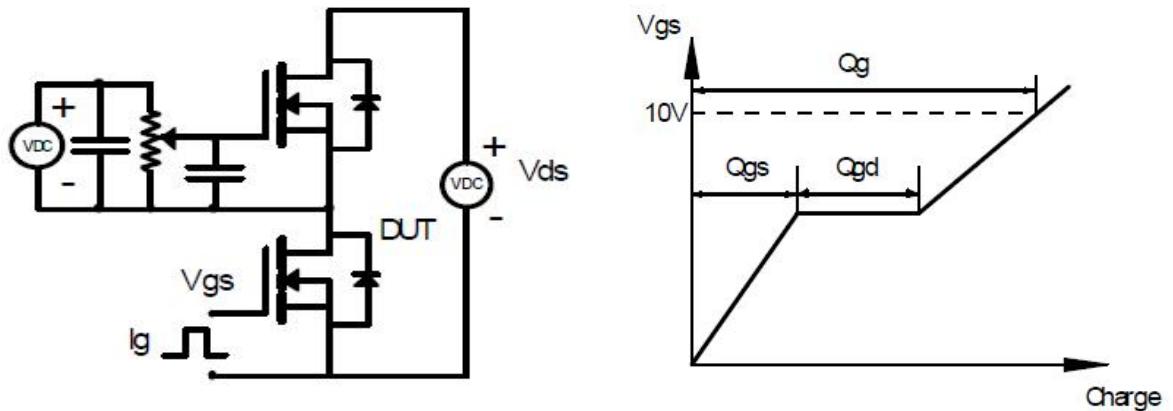
**Figure 9: Normalized Maximum Transient Thermal Impedance**



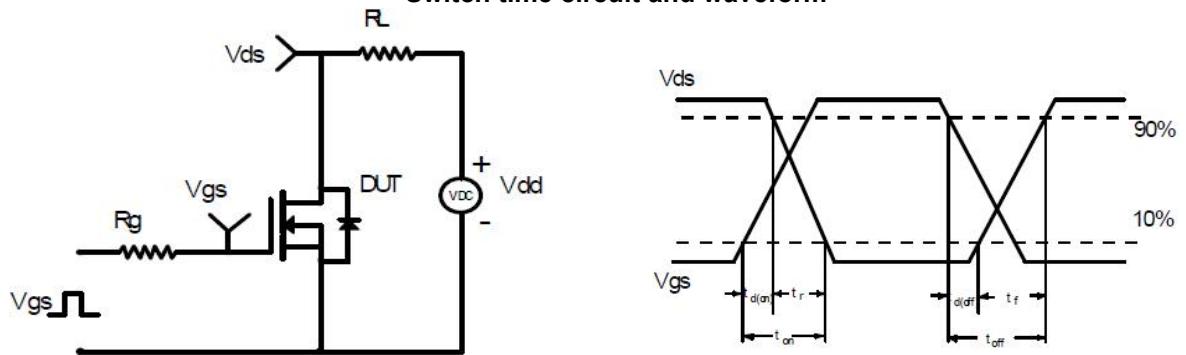
**Figure 10: On-Resistance vs.  $V_{GS}$**

## Test circuits and Waveforms:

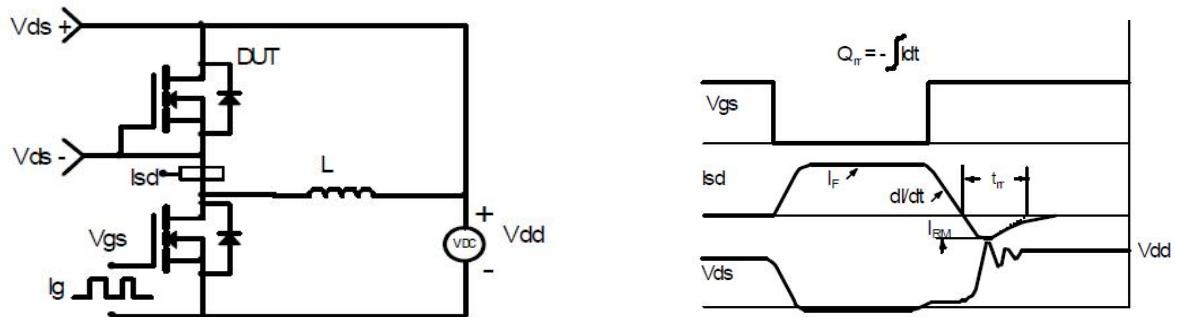
Gate charge circuit and waveform



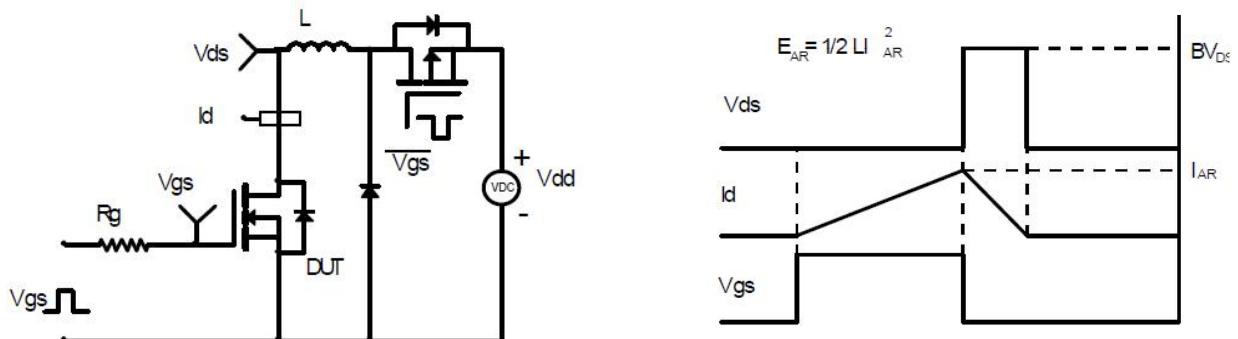
Switch time circuit and waveform



Reverse recovery test circuit and waveform

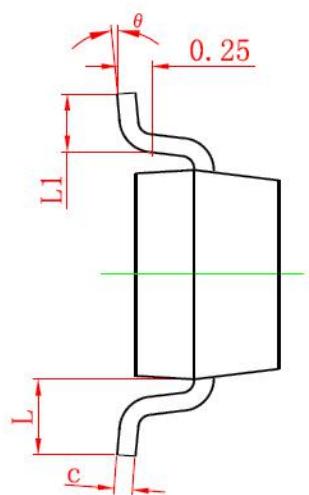
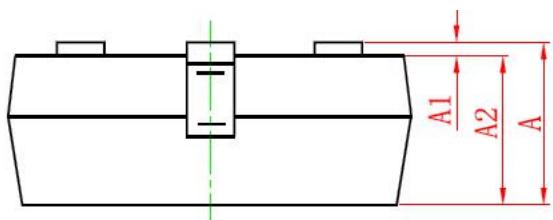
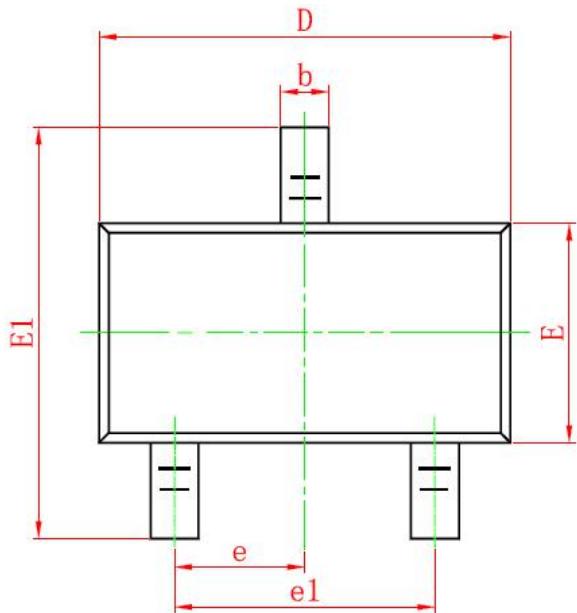


EAS test circuit and waveform



## Mechanical Data: SOT23

Dimensions in Millimeters (UNIT:mm)



Symbol	Dimensions in	
	MIN.	MAX.
A	0.9	1.15
A1	0	0.1
A2	0.9	1.05
b	0.3	0.5
c	0.08	0.15
D	2.8	3
E	1.2	1.4
E1	2.25	2.55
e	0.950TYP	
e1	1.8	2
L	0.550REF	
L1	0.3	0.5
$\theta$	0°	8°

## PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
3415	WT3415	SOT-23	Ø330mm	12mm	3000 units